

**Notice of References Cited**

Application/Control No.

10/596,381

Applicant(s)/Patent Under  
Reexamination  
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Examiner

JENNIFER ZUBAJLO

Art Unit

2629

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0063806	05-2002	Ouchi et al.	348/745
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	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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